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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	416
Number of Logic Elements/Cells	4160
Total RAM Bits	53248
Number of I/O	252
Number of Gates	263000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	324-BGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep20k100fi324-3

Email: info@E-XFL.COM

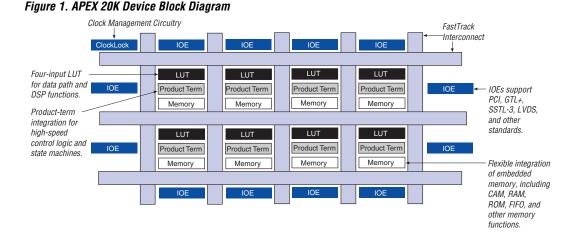
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Functional Description

APEX 20K devices incorporate LUT-based logic, product-term-based logic, and memory into one device. Signal interconnections within APEX 20K devices (as well as to and from device pins) are provided by the FastTrack[®] Interconnect—a series of fast, continuous row and column channels that run the entire length and width of the device.

Each I/O pin is fed by an I/O element (IOE) located at the end of each row and column of the FastTrack Interconnect. Each IOE contains a bidirectional I/O buffer and a register that can be used as either an input or output register to feed input, output, or bidirectional signals. When used with a dedicated clock pin, these registers provide exceptional performance. IOEs provide a variety of features, such as 3.3-V, 64-bit, 66-MHz PCI compliance; JTAG BST support; slew-rate control; and tri-state buffers. APEX 20KE devices offer enhanced I/O support, including support for 1.8-V I/O, 2.5-V I/O, LVCMOS, LVTTL, LVPECL, 3.3-V PCI, PCI-X, LVDS, GTL+, SSTL-2, SSTL-3, HSTL, CTT, and 3.3-V AGP I/O standards.

The ESB can implement a variety of memory functions, including CAM, RAM, dual-port RAM, ROM, and FIFO functions. Embedding the memory directly into the die improves performance and reduces die area compared to distributed-RAM implementations. Moreover, the abundance of cascadable ESBs ensures that the APEX 20K device can implement multiple wide memory blocks for high-density designs. The ESB's high speed ensures it can implement small memory blocks without any speed penalty. The abundance of ESBs ensures that designers can create as many different-sized memory blocks as the system requires. Figure 1 shows an overview of the APEX 20K device.



Altera Corporation 9

LE Operating Modes

The APEX 20K LE can operate in one of the following three modes:

- Normal mode
- Arithmetic mode
- Counter mode

Each mode uses LE resources differently. In each mode, seven available inputs to the LE—the four data inputs from the LAB local interconnect, the feedback from the programmable register, and the carry-in and cascade-in from the previous LE—are directed to different destinations to implement the desired logic function. LAB-wide signals provide clock, asynchronous clear, asynchronous preset, asynchronous load, synchronous clear, synchronous load, and clock enable control for the register. These LAB-wide signals are available in all LE modes.

The Quartus II software, in conjunction with parameterized functions such as LPM and DesignWare functions, automatically chooses the appropriate mode for common functions such as counters, adders, and multipliers. If required, the designer can also create special-purpose functions that specify which LE operating mode to use for optimal performance. Figure 8 shows the LE operating modes.

Select Vertical I/O Pins IOE IOE FastRow Interconnect IOE IOE Drive Local Interconnect FastRow Drives Local Interconnect and FastRow Interconnect in Two MegaLAB Structures Interconnect Local Interconnect LEs MegaLAB MegaLAB *LABs*

Figure 12. APEX 20KE FastRow Interconnect

Table 9 summarizes how various elements of the APEX 20K architecture drive each other.

The programmable register also supports an asynchronous clear function. Within the ESB, two asynchronous clears are generated from global signals and the local interconnect. Each macrocell can either choose between the two asynchronous clear signals or choose to not be cleared. Either of the two clear signals can be inverted within the ESB. Figure 15 shows the ESB control logic when implementing product-terms.

Dedicated Clocks Global Signals Local Interconnect Local Interconnect Local Interconnect Local Interconnect CLR1 CLKENA2 CLK1 CLKENA1 CLR₂

Figure 15. ESB Product-Term Mode Control Logic

Note to Figure 15:

(1) APEX 20KE devices have four dedicated clocks.

Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 32 product terms to feed the macrocell OR logic directly, with two product terms provided by the macrocell and 30 parallel expanders provided by the neighboring macrocells in the ESB.

The Quartus II software Compiler can allocate up to 15 sets of up to two parallel expanders per set to the macrocells automatically. Each set of two parallel expanders incurs a small, incremental timing delay. Figure 16 shows the APEX 20K parallel expanders.

Implementing Logic in ROM

In addition to implementing logic with product terms, the ESB can implement logic functions when it is programmed with a read-only pattern during configuration, creating a large LUT. With LUTs, combinatorial functions are implemented by looking up the results, rather than by computing them. This implementation of combinatorial functions can be faster than using algorithms implemented in general logic, a performance advantage that is further enhanced by the fast access times of ESBs. The large capacity of ESBs enables designers to implement complex functions in one logic level without the routing delays associated with linked LEs or distributed RAM blocks. Parameterized functions such as LPM functions can take advantage of the ESB automatically. Further, the Quartus II software can implement portions of a design with ESBs where appropriate.

Programmable Speed/Power Control

APEX 20K ESBs offer a high-speed mode that supports very fast operation on an ESB-by-ESB basis. When high speed is not required, this feature can be turned off to reduce the ESB's power dissipation by up to 50%. ESBs that run at low power incur a nominal timing delay adder. This Turbo BitTM option is available for ESBs that implement product-term logic or memory functions. An ESB that is not used will be powered down so that it does not consume DC current.

Designers can program each ESB in the APEX 20K device for either high-speed or low-power operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths operate at reduced power.

I/O Structure

The APEX 20K IOE contains a bidirectional I/O buffer and a register that can be used either as an input register for external data requiring fast setup times, or as an output register for data requiring fast clock-to-output performance. IOEs can be used as input, output, or bidirectional pins. For fast bidirectional I/O timing, LE registers using local routing can improve setup times and OE timing. The Quartus II software Compiler uses the programmable inversion option to invert signals from the row and column interconnect automatically where appropriate. Because the APEX 20K IOE offers one output enable per pin, the Quartus II software Compiler can emulate open-drain operation efficiently.

The APEX 20K IOE includes programmable delays that can be activated to ensure zero hold times, minimum clock-to-output times, input IOE register-to-core register transfers, or core-to-output IOE register transfers. A path in which a pin directly drives a register may require the delay to ensure zero hold time, whereas a path in which a pin drives a register through combinatorial logic may not require the delay.

For designs that require both a multiplied and non-multiplied clock, the clock trace on the board can be connected to CLK2p. Table 14 shows the combinations supported by the ClockLock and ClockBoost circuitry. The CLK2p pin can feed both the ClockLock and ClockBoost circuitry in the APEX 20K device. However, when both circuits are used, the other clock pin (CLK1p) cannot be used.

Table 14. Multiplication Factor Combinations						
Clock 1 Clock 2						
×1	×1					
×1,×2	×2					
×1, ×2, ×4	×4					

APEX 20KE ClockLock Feature

APEX 20KE devices include an enhanced ClockLock feature set. These devices include up to four PLLs, which can be used independently. Two PLLs are designed for either general-purpose use or LVDS use (on devices that support LVDS I/O pins). The remaining two PLLs are designed for general-purpose use. The EP20K200E and smaller devices have two PLLs; the EP20K300E and larger devices have four PLLs.

The following sections describe some of the features offered by the APEX 20KE PLLs.

External PLL Feedback

The ClockLock circuit's output can be driven off-chip to clock other devices in the system; further, the feedback loop of the PLL can be routed off-chip. This feature allows the designer to exercise fine control over the I/O interface between the APEX 20KE device and another high-speed device, such as SDRAM.

Clock Multiplication

The APEX 20KE ClockBoost circuit can multiply or divide clocks by a programmable number. The clock can be multiplied by $m/(n \times k)$ or $m/(n \times v)$, where m and k range from 2 to 160, and n and v range from 1 to 16. Clock multiplication and division can be used for time-domain multiplexing and other functions, which can reduce design LE requirements.

Notes to Table 16:

- (1) To implement the ClockLock and ClockBoost circuitry with the Quartus II software, designers must specify the input frequency. The Quartus II software tunes the PLL in the ClockLock and ClockBoost circuitry to this frequency. The f_{CLKDEV} parameter specifies how much the incoming clock can differ from the specified frequency during device operation. Simulation does not reflect this parameter.
- (2) Twenty-five thousand parts per million (PPM) equates to 2.5% of input clock period.
- (3) During device configuration, the ClockLock and ClockBoost circuitry is configured before the rest of the device. If the incoming clock is supplied during configuration, the ClockLock and ClockBoost circuitry locks during configuration because the t_{LOCK} value is less than the time required for configuration.
- (4) The t_{IITTER} specification is measured under long-term observation.

Tables 17 and 18 summarize the ClockLock and ClockBoost parameters for APEX 20KE devices.

Table 17. APEX 20KE ClockLock & ClockBoost Parameters Note (1)								
Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
t _R	Input rise time				5	ns		
t _F	Input fall time				5	ns		
t _{INDUTY}	Input duty cycle		40		60	%		
t _{INJITTER}	Input jitter peak-to-peak				2% of input period	peak-to- peak		
t _{OUTJITTER}	Jitter on ClockLock or ClockBoost- generated clock				0.35% of output period	RMS		
t _{OUTDUTY}	Duty cycle for ClockLock or ClockBoost-generated clock		45		55	%		
t _{LOCK} (2), (3)	Time required for ClockLock or ClockBoost to acquire lock				40	μs		

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

All APEX 20K devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1-1990 specification. JTAG boundary-scan testing can be performed before or after configuration, but not during configuration. APEX 20K devices can also use the JTAG port for configuration with the Quartus II software or with hardware using either Jam Files (.jam) or Jam Byte-Code Files (.jbc). Finally, APEX 20K devices use the JTAG port to monitor the logic operation of the device with the SignalTap embedded logic analyzer. APEX 20K devices support the JTAG instructions shown in Table 19. Although EP20K1500E devices support the JTAG BYPASS and SignalTap instructions, they do not support boundary-scan testing or the use of the JTAG port for configuration.

Table 19. APEX 20K JT	AG Instructions
JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap embedded logic analyzer.
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS (1)	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ICR Instructions	Used when configuring an APEX 20K device via the JTAG port with a MasterBlaster TM or ByteBlasterMV TM download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.
SignalTap Instructions (1)	Monitors internal device operation with the SignalTap embedded logic analyzer.

Note to Table 19:

(1) The EP20K1500E device supports the JTAG BYPASS instruction and the SignalTap instructions.

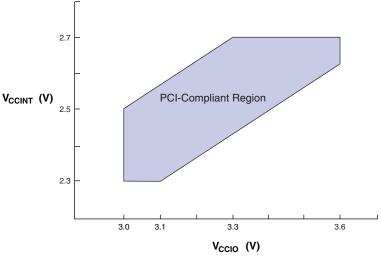


Figure 33. Relationship between V_{CCIO} & V_{CCINT} for 3.3-V PCI Compliance

Figure 34 shows the typical output drive characteristics of APEX 20K devices with 3.3-V and 2.5-V $V_{\rm CCIO}$. The output driver is compatible with the 3.3-V *PCI Local Bus Specification, Revision 2.2* (when VCCIO pins are connected to 3.3 V). 5-V tolerant APEX 20K devices in the -1 speed grade are 5-V PCI compliant over all operating conditions.

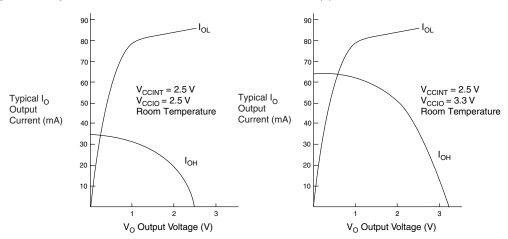


Figure 34. Output Drive Characteristics of APEX 20K Device Note (1)

Note to Figure 34:

(1) These are transient (AC) currents.

Note to Tables 32 and 33:

(1) These timing parameters are sample-tested only.

Tables 34 through 37 show APEX 20KE LE, ESB, routing, and functional timing microparameters for the f_{MAX} timing model.

Table 34. APEX 20KE LE Timing Microparameters						
Symbol Parameter						
t _{SU}	LE register setup time before clock					
t _H	LE register hold time after clock					
t _{CO}	LE register clock-to-output delay					
t _{LUT}	LUT delay for data-in to data-out					

Table 35. APE.	X 20KE ESB Timing Microparameters
Symbol	Parameter
t _{ESBARC}	ESB Asynchronous read cycle time
t _{ESBSRC}	ESB Synchronous read cycle time
t _{ESBAWC}	ESB Asynchronous write cycle time
t _{ESBSWC}	ESB Synchronous write cycle time
t _{ESBWASU}	ESB write address setup time with respect to WE
t _{ESBWAH}	ESB write address hold time with respect to WE
t _{ESBWDSU}	ESB data setup time with respect to WE
t _{ESBWDH}	ESB data hold time with respect to WE
t _{ESBRASU}	ESB read address setup time with respect to RE
t _{ESBRAH}	ESB read address hold time with respect to RE
t _{ESBWESU}	ESB WE setup time before clock when using input register
t _{ESBWEH}	ESB WE hold time after clock when using input register
t _{ESBDATASU}	ESB data setup time before clock when using input register
t _{ESBDATAH}	ESB data hold time after clock when using input register
t _{ESBWADDRSU}	ESB write address setup time before clock when using input registers
t _{ESBRADDRSU}	ESB read address setup time before clock when using input registers
t _{ESBDATACO1}	ESB clock-to-output delay when using output registers
t _{ESBDATACO2}	ESB clock-to-output delay without output registers
t _{ESBDD}	ESB data-in to data-out delay for RAM mode
t _{PD}	ESB Macrocell input to non-registered output
t _{PTERMSU}	ESB Macrocell register setup time before clock
t _{PTERMCO}	ESB Macrocell register clock-to-output delay

Table 43. EP20K100 External Timing Parameters									
Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit		
	Min	Max	Min	Max	Min	Max			
t _{INSU} (1)	2.3		2.8		3.2		ns		
t _{INH} (1)	0.0		0.0		0.0		ns		
t _{OUTCO} (1)	2.0	4.5	2.0	4.9	2.0	6.6	ns		
t _{INSU} (2)	1.1		1.2		-		ns		
t _{INH} (2)	0.0		0.0		-		ns		
t _{OUTCO} (2)	0.5	2.7	0.5	3.1	_	4.8	ns		

Symbol	-1 Speed Grade		-2 Spee	-2 Speed Grade		d Grade	Unit
	Min	Max	Min	Max	Min	Max	1
t _{INSUBIDIR} (1)	2.3		2.8		3.2		ns
t _{INHBIDIR} (1)	0.0		0.0		0.0		ns
toutcobidir (1)	2.0	4.5	2.0	4.9	2.0	6.6	ns
t _{XZBIDIR} (1)		5.0		5.9		6.9	ns
t _{ZXBIDIR} (1)		5.0		5.9		6.9	ns
t _{INSUBIDIR} (2)	1.0		1.2		-		ns
t _{INHBIDIR} (2)	0.0		0.0		-		ns
toutcobidir (2)	0.5	2.7	0.5	3.1	-	-	ns
t _{XZBIDIR} (2)		4.3		5.0		_	ns
t _{ZXBIDIR} (2)		4.3		5.0		_	ns

Table 45. EP20K200 External Timing Parameters									
Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit		
	Min	Max	Min	Max	Min	Max			
t _{INSU} (1)	1.9		2.3		2.6		ns		
t _{INH} (1)	0.0		0.0		0.0		ns		
t _{OUTCO} (1)	2.0	4.6	2.0	5.6	2.0	6.8	ns		
t _{INSU} (2)	1.1		1.2		-		ns		
t _{INH} (2)	0.0		0.0		-		ns		
t _{оитсо} <i>(2)</i>	0.5	2.7	0.5	3.1	-	_	ns		

Tables 55 through 60 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K60E APEX 20KE devices.

Symbol	-	1		-2	-3		Unit	
	Min	Max	Min	Max	Min	Max		
t _{SU}	0.17		0.15		0.16		ns	
t _H	0.32		0.33		0.39		ns	
t _{CO}		0.29		0.40		0.60	ns	
t _{LUT}		0.77		1.07		1.59	ns	

Table 62. EP20K	I GOL IMAX LOL	, iming mid	1		T		1
Symbol	-	1		-2		3	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.61		1.84		1.97	ns
t _{ESBSRC}		2.57		2.97		3.20	ns
t _{ESBAWC}		0.52		4.09		4.39	ns
t _{ESBSWC}		3.17		3.78		4.09	ns
t _{ESBWASU}	0.56		6.41		0.63		ns
t _{ESBWAH}	0.48		0.54		0.55		ns
t _{ESBWDSU}	0.71		0.80		0.81		ns
t _{ESBWDH}	.048		0.54		0.55		ns
t _{ESBRASU}	1.57		1.75		1.87		ns
t _{ESBRAH}	0.00		0.00		0.20		ns
t _{ESBWESU}	1.54		1.72		1.80		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	-0.16		-0.20		-0.20		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.12		0.08		0.13		ns
t _{ESBRADDRSU}	0.17		0.15		0.19		ns
t _{ESBDATACO1}		1.20		1.39		1.52	ns
t _{ESBDATACO2}		2.54		2.99		3.22	ns
t _{ESBDD}		3.06		3.56		3.85	ns
t _{PD}		1.73		2.02		2.20	ns
t _{PTERMSU}	1.11		1.26		1.38		ns
t _{PTERMCO}		1.19		1.40		1.08	ns

Table 63. EP2	0K100E f _{MAX} 1	Routing Delays	s				
Symbol	-	1	-	-2		Unit	
	Min	Max	Min	Max	Min	Max	1
t _{F1-4}		0.24		0.27		0.29	ns
t _{F5-20}		1.04		1.26		1.52	ns
t _{F20+}		1.12		1.36		1.86	ns

Table 76. EP2	OK200E Minin	num Pulse W	idth Timing Pa	arameters			
Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{CH}	1.36		2.44		2.65		ns
t _{CL}	1.36		2.44		2.65		ns
t _{CLRP}	0.18		0.19		0.21		ns
t _{PREP}	0.18		0.19		0.21		ns
t _{ESBCH}	1.36		2.44		2.65		ns
t _{ESBCL}	1.36		2.44		2.65		ns
t _{ESBWP}	1.18		1.48		1.76		ns
t _{ESBRP}	0.95		1.17		1.41		ns

Symbol	-1		-	-2		-3	
	Min	Max	Min	Max	Min	Max	
t _{INSU}	2.24		2.35		2.47		ns
t _{INH}	0.00		0.00		0.00		ns
t _{outco}	2.00	5.12	2.00	5.62	2.00	6.11	ns
t _{INSUPLL}	2.13		2.07		-		ns
t _{INHPLL}	0.00		0.00		-		ns
t _{OUTCOPLL}	0.50	3.01	0.50	3.36	-	-	ns

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{CH}	1.25		1.43		1.67		ns
t _{CL}	1.25		1.43		1.67		ns
t _{CLRP}	0.19		0.26		0.35		ns
t _{PREP}	0.19		0.26		0.35		ns
t _{ESBCH}	1.25		1.43		1.67		ns
t _{ESBCL}	1.25		1.43		1.67		ns
t _{ESBWP}	1.25		1.71		2.28		ns
t _{ESBRP}	1.01		1.38		1.84		ns

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{INSU}	2.31		2.44		2.57		ns
t _{INH}	0.00		0.00		0.00		ns
t _{OUTCO}	2.00	5.29	2.00	5.82	2.00	6.24	ns
t _{INSUPLL}	1.76		1.85		-		ns
t _{INHPLL}	0.00		0.00		-		ns
toutcople	0.50	2.65	0.50	2.95	_	-	ns

Symbol	-1		-	2	-	3	Unit
	Min	Max	Min	Max	Min	Max	
t _{INSUBIDIR}	2.77		2.85		3.11		ns
t _{INHBIDIR}	0.00		0.00		0.00		ns
t _{OUTCOBIDIR}	2.00	5.29	2.00	5.82	2.00	6.24	ns
t _{XZBIDIR}		7.59		8.30		9.09	ns
t _{ZXBIDIR}		7.59		8.30		9.09	ns
t _{INSUBIDIRPLL}	2.50		2.76		-		ns
t _{INHBIDIRPLL}	0.00		0.00		-		ns
toutcobidirpll	0.50	2.65	0.50	2.95	-	-	ns
t _{XZBIDIRPLL}		5.00		5.43		-	ns
tzxbidirpll		5.00		5.43		-	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t _{INSUBIDIR}	2.93		3.23		3.44		ns
t _{INHBIDIR}	0.00		0.00		0.00		ns
toutcobidir	2.00	5.25	2.00	5.79	2.00	6.32	ns
t _{XZBIDIR}		5.95		6.77		7.12	ns
tzxbidir		5.95		6.77		7.12	ns
t _{INSUBIDIRPLL}	4.31		4.76		-		ns
tinhbidirpll	0.00		0.00		-		ns
toutcobidirpll	0.50	2.25	0.50	2.45	-	-	ns
txzbidirpll		2.94		3.43		-	ns
tzxbidirpll		2.94		3.43		-	ns

Tables 91 through 96 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K600E APEX 20KE devices.

Table 91. EP20K600E f _{MAX} LE Timing Microparameters										
Symbol	-1 Spee	d Grade	-2 Spee	ed Grade	-3 Spee	-3 Speed Grade				
	Min	Max	Min	Max	Min	Max				
t _{SU}	0.16		0.16		0.17		ns			
t _H	0.29		0.33		0.37		ns			
t _{CO}		0.65		0.38		0.49	ns			
t _{LUT}		0.70		1.00		1.30	ns			

Tables 97 through 102 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K1000E APEX 20KE devices.

Table 97. EP20K1000E f _{MAX} LE Timing Microparameters										
Symbol	-1 Spee	d Grade	-2 Spee	ed Grade	-3 Spee	d Grade	Unit			
	Min	Max	Min	Max	Min	Max				
t _{SU}	0.25		0.25		0.25		ns			
t _H	0.25		0.25		0.25		ns			
t _{CO}		0.28		0.32		0.33	ns			
t _{LUT}		0.80		0.95		1.13	ns			

Symbol	-1 Spee	d Grade	-2 Spe	ed Grade	-3 Spee	d Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.78		2.02		1.95	ns
t _{ESBSRC}		2.52		2.91		3.14	ns
t _{ESBAWC}		3.52		4.11		4.40	ns
t _{ESBSWC}		3.23		3.84		4.16	ns
t _{ESBWASU}	0.62		0.67		0.61		ns
t _{ESBWAH}	0.41		0.55		0.55		ns
t _{ESBWDSU}	0.77		0.79		0.81		ns
t _{ESBWDH}	0.41		0.55		0.55		ns
t _{ESBRASU}	1.74		1.92		1.85		ns
t _{ESBRAH}	0.00		0.01		0.23		ns
t _{ESBWESU}	2.07		2.28		2.41		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.25		0.27		0.29		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.11		0.04		0.11		ns
t _{ESBRADDRSU}	0.14		0.11		0.16		ns
t _{ESBDATACO1}		1.29		1.50		1.63	ns
t _{ESBDATACO2}		2.55		2.99		3.22	ns
t _{ESBDD}		3.12		3.57		3.85	ns
t _{PD}		1.84		2.13		2.32	ns
t _{PTERMSU}	1.08		1.19		1.32		ns

1.53

1.66

ns

1.31

 t_{PTERMCO}

Symbol	-1 Speed Grade		-2 Speed	-2 Speed Grade		Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{CH}	1.25		1.43		1.67		ns
t _{CL}	1.25		1.43		1.67		ns
t _{CLRP}	0.20		0.20		0.20		ns
t _{PREP}	0.20		0.20		0.20		ns
t _{ESBCH}	1.25		1.43		1.67		ns
t _{ESBCL}	1.25		1.43		1.67		ns
t _{ESBWP}	1.28		1.51		1.65		ns
t _{ESBRP}	1.11		1.29		1.41		ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t _{INSU}	3.09		3.30		3.58		ns
t _{INH}	0.00		0.00		0.00		ns
t _{OUTCO}	2.00	6.18	2.00	6.81	2.00	7.36	ns
t _{INSUPLL}	1.94		2.08		-		ns
t _{INHPLL}	0.00		0.00		-		ns
toutcople	0.50	2.67	0.50	2.99	-	-	ns

Revision History

The information contained in the *APEX 20K Programmable Logic Device Family Data Sheet* version 5.1 supersedes information published in previous versions.

Version 5.1

APEX 20K Programmable Logic Device Family Data Sheet version 5.1 contains the following changes:

- In version 5.0, the VI input voltage spec was updated in Table 28 on page 63.
- In version 5.0, *Note* (5) to Tables 27 through 30 was revised.
- Added *Note* (2) to Figure 21 on page 33.

Version 5.0

APEX 20K Programmable Logic Device Family Data Sheet version 5.0 contains the following changes:

- Updated Tables 23 through 26. Removed 2.5-V operating condition tables because all APEX 20K devices are now 5.0-V tolerant.
- Updated conditions in Tables 33, 38 and 39.
- Updated data for t_{ESBDATAH} parameter.

Version 4.3

APEX 20K Programmable Logic Device Family Data Sheet version 4.3 contains the following changes:

- Updated Figure 20.
- Updated *Note* (2) to Table 13.
- Updated notes to Tables 27 through 30.

Version 4.2

APEX 20K Programmable Logic Device Family Data Sheet version 4.2 contains the following changes:

- Updated Figure 29.
- Updated *Note* (1) to Figure 29.